

**Search Notes**

Application/Control No.

10/822,898

Examiner

Ba Huynh

Applicant(s)/Patent under  
Reexamination

CLAY ET AL.

Art Unit

2179

**SEARCHED**

Class	Subclass	Date	Examiner
715	810	11/17/2005	HB
	817		
	818		
	815		
	821		
	830		

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East: USpat, USppgpub, Epo, Jpo, Derwent, IBM-tdb files searched.	11/17/2005	HB

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner